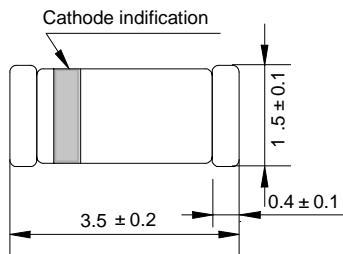


Silicon Epitaxial Planar Diodes

Applications

General purposes

BAV100---BAV103



LL-34(SOD-80) Dimensions in millimeters

Absolute Maximum Ratings

T_j = 25°C

Parameter	Test Conditions	Type	Symbol	Value	Unit
Repetitive peak reverse voltage		BAV100	V _{RRM}	60	V
		BAV101	V _{RRM}	120	V
		BAV102	V _{RRM}	200	V
		BAV103	V _{RRM}	250	V
Reverse voltage		BAV100	V _R	50	V
		BAV101	V _R	100	V
		BAV102	V _R	150	V
		BAV103	V _R	200	V
Peak forward surge current	t _p =1s		I _{FSM}	1	A
Repetitive peak forward current			I _{FRM}	625	mA
Forward current			I _F	250	mA
Power dissipation			P _V	500	mW
Junction temperature			T _j	175	°C
Storage temperature range			T _{stg}	-65...+175	°C

Maximum Thermal Resistance

T_j = 25°C

Parameter	Test Conditions	Symbol	Value	Unit
Junction lead		R _{thJL}	350	K/W
Junction ambient	on PC board 50mmx50mmx1.6mm	R _{thJA}	500	K/W

Electrical Characteristics $T_j = 25^\circ\text{C}$

BAV100---BAV103

Parameter	Test Conditions	Type	Symbol	Min	Typ	Max	Unit
Forward voltage	$I_F=100\text{mA}$		V_F			1	V
Reverse current	$V_R=50\text{V}$	BAV100	I_R			100	nA
	$V_R=100\text{V}$	BAV101	I_R			100	nA
	$V_R=150\text{V}$	BAV102	I_R			100	nA
	$V_R=200\text{V}$	BAV103	I_R			100	nA
	$T_j=100^\circ\text{C}, V_R= 50\text{V}$	BAV100	I_R			15	μA
	$T_j=100^\circ\text{C}, V_R=100\text{V}$	BAV101	I_R			15	μA
	$T_j=100^\circ\text{C}, V_R=150\text{V}$	BAV102	I_R			15	μA
	$T_j=100^\circ\text{C}, V_R=200\text{V}$	BAV103	I_R			15	μA
Breakdown voltage	$I_R=100\mu\text{A}, t_p/T=0.01, t_p=0.3\text{ms}$	BAV100	$V_{(BR)}$	60			V
		BAV101	$V_{(BR)}$	120			V
		BAV102	$V_{(BR)}$	200			V
		BAV103	$V_{(BR)}$	250			V
Diode capacitance	$V_R=0, f=1\text{MHz}$		C_D		1.5		pF
Differential forward resistance	$I_F=10\text{mA}$		r_f		5		Ω
Reverse recovery time	$I_F=I_R=30\text{mA}, i_R=3\text{mA}, R_L=100\Omega$		t_{rr}			50	ns

Characteristics ($T_j = 25^\circ\text{C}$ unless otherwise specified)

